

Search Notes



Application/Control No.

10/784,326

Examiner

Kin-Chan Chen

Applicant(s)/Patent under
Reexamination

LEE ET AL.

Art Unit

1765

SEARCHED

Class	Subclass	Date	Examiner
438	700	11/23/2005	KCC
	706		
	719		
	720		
	723		
438	724		
	221		
	296		
438	427	11/23/05	KCC
updated		4/10/06	KCC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
438	700	4/10/06	KCC
	706		
	719		
	720		
	723		
	724		
	221		
	296		
438	427	4/10/06	KCC

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
East Keyword search US PAT, USPG-pub. Epo, Jpo, Perwent TBM-TOB, inventor search	11/18/2005	KCC
updated	4/10/06	KCC